

Wavefront_Confirmation

ANSI/OEOSC OP Wavefront Measurement Standard Meeting, January 20, 2007

Participation	Company	Job Title	Title	Last	First	Attendance
Member	APOMA		Mr.	Czajkowski	Walter	YES
Member	Brookhaven National Lab.		Mr.	Takacs	Peter	YES
Member	Consultant		Mr.	Williamson	Ray	YES
Member	Corning Tropel	Component Metrology Manager	Mr.	VanKerkhove	Steven	YES
Member	IEEE/LEOS (NIST)	Group Leader	Ms.	Dowell	Marla	YES
Member	JDSU	Quality Engineer	Mr.	Boultbee	Gordon	YES
Member	JDSU		Mr.	Catching	Benjamin	Phone
Member	Research Electro-Optics, Inc.	VP of Engineering & Chief Competitive Officer	Mr.	Turner	Trey	NO
Member	SPIE (Endelman Enterprises)	Consultant	Mr.	Endelman	Lincoln	YES
Member	Xyratex	Senior Staff Scientist	Mr.	Brunfeld	Andrei	YES
Member	Zygo Corporation	Director Operations, Metrology	Mr.	Aikens	David	YES

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YES 9
Phone 1
NO 1
Attending 10
Quorum 6

Observers						
Participation	Company	Job Title	Title	Last	First	Attendance
Observer	4DTechnology		Mr.	Martinek	Steven	YES
Observer	Argonne National Laboratory		Mr.	Assoufid	Lahsen	YES
Observer	Asml Optics LLC			Bajuk	Dan	
Observer	College of Optics & Photonics: CREOL & FPCE	Associate Professor of Optics & ECE	Dr.	Harvey	James	YES
Observer	Lawrence Livermore National Laboratory		Mr.	McBurney	Michael	
Observer	National Institute of Standards and Technology	Physicist	Dr.	Germer	Thomas	
Observer	QED Technologies		Mr.	Dumas	Paul	YES
Observer	Triptar Lens Co., Inc.	President	Mr.	Krisiloff	Alan	YES
Observer	University of Central Florida	Dir, Res & Admin, College of Opt & Pho: CREOL & FPCE	Dr.	Pearson	James	
Observer	Zygo Corporation		Mr.	Evans	Chris	
Observer	Zygo Corporation	V P Marketing	Mr.	Smythe	Robert	

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YES 5
Phone 0
NO 0
Attending 5